Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,681	CHEN ET AL.
Examiner	Art Unit
Yicun Wu	2165

SEARCHED					
Class	Subclass	Date	Examiner		
707	1-10, 100- 104.1 200-206	6/5/2006	YW		
705	26	6/5/2006	YW		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
-				

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	6/5/2006	ΥW
acm ieee citeseer internet Search stratagy attached	6/5/2006	YW
consulted Apu Mofiz	6/5/2006	ΥW